

Optimization of the ATLAS Muon Detector Readout for high counting rates

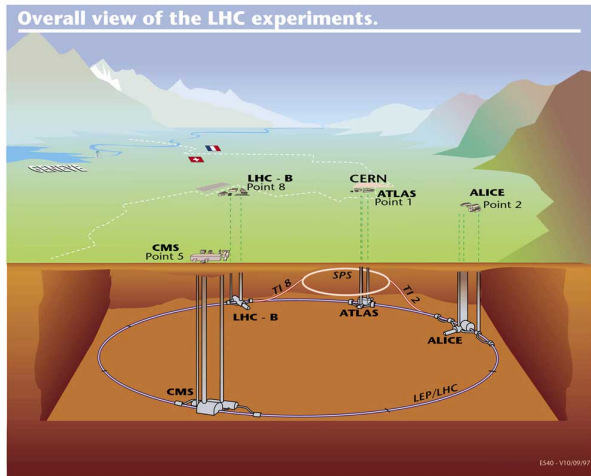
Sebastian Ott

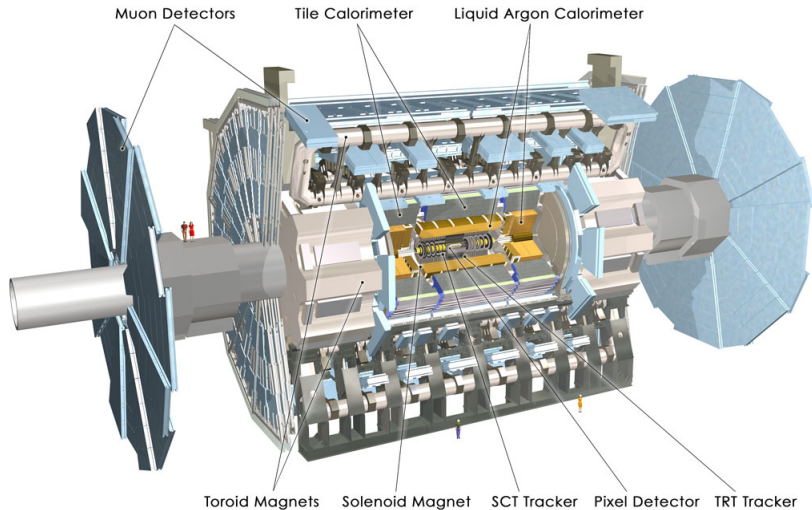
July 21, 2013

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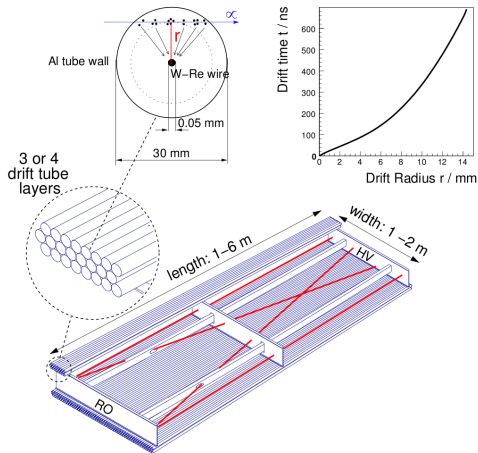
- Proton-Proton collision at 7 - 8 TeV (2012)
- Aim of energy increase: 13 TeV (2015)
- Design luminosity: $10^{34} \text{ cm}^{-2}\text{s}^{-1}$ (2015)
- Luminosity increase to $7 \cdot 10^{34} \text{ cm}^{-2}\text{s}^{-1}$ (2023)





ATLAS Monitored Drift Tube (MDT)-Chamber

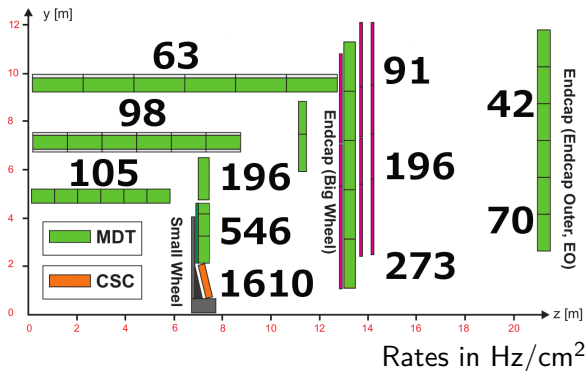
- Tube diameter 30 mm (currently mounted)
- Gasmixture Ar/CO₂ (93/7)
- Pressure: 3 bar
- Voltage: 3080 V
- Max. drifttime: 700 ns
- Nonlinear r-t-relation
- Background rate capability: 300 kHz/tube (500 Hz/cm²)



Upcoming Requirements

Background:

- Photons
- Neutrons
- Background \propto luminosity



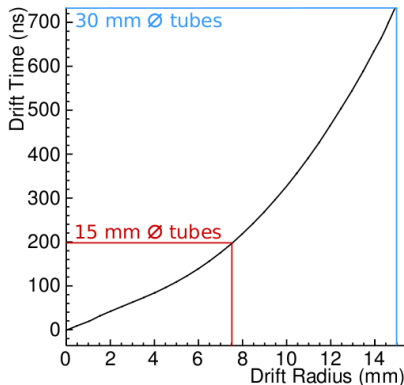
- Higher signal rates

⇒ In some regions the MDT-chambers will come to their limits

Improvement of the MDT-Chambers - sMDT

Reducing the diameter to 15 mm

- Shorter max. drifttime
 - ⇒ Deadtime can be reduced
 - ⇒ Fewer masking effects

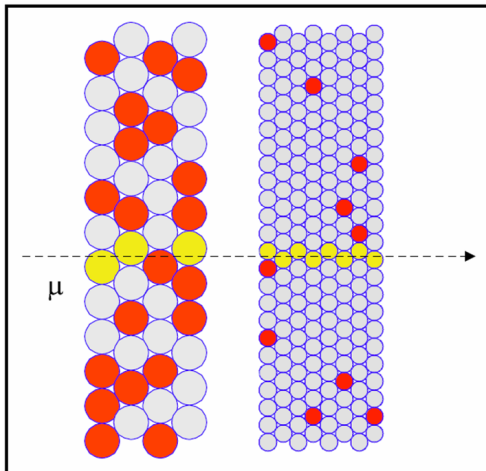


Improvement of the MDT-Chambers - sMDT

Reducing the diameter to 15 mm

- More tubes per chamber

⇒ Lower occupancy

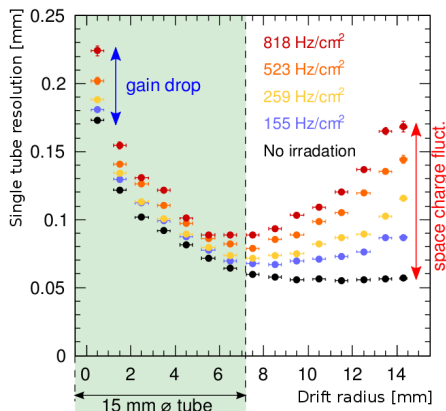
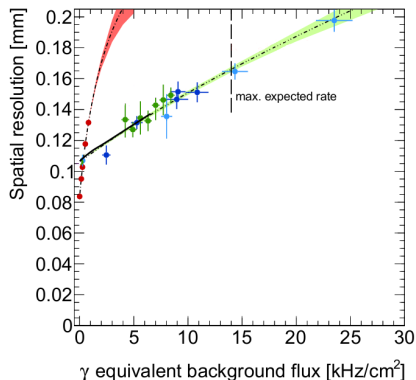


Improvement of the MDT-Chambers - sMDT

Reducing the diameter to 15 mm

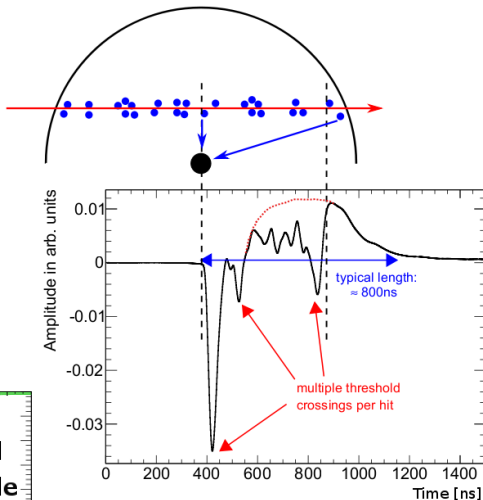
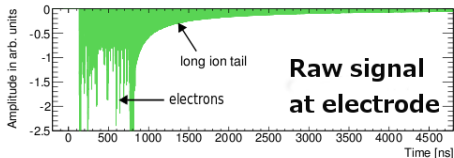
- Less space charge fluctuations

⇒ Better resolution



Improvement of the MDT-Chambers - sMDT

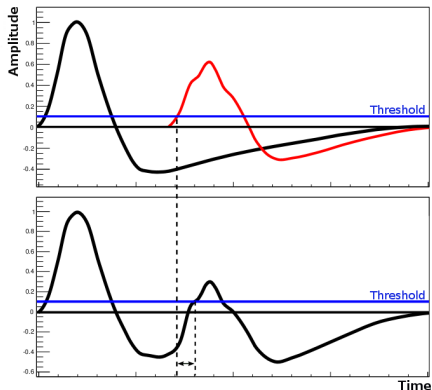
- e^- -Ion-pairs
- Fast e^- signal is interesting
- Multiple threshold crossings for one Muon possible



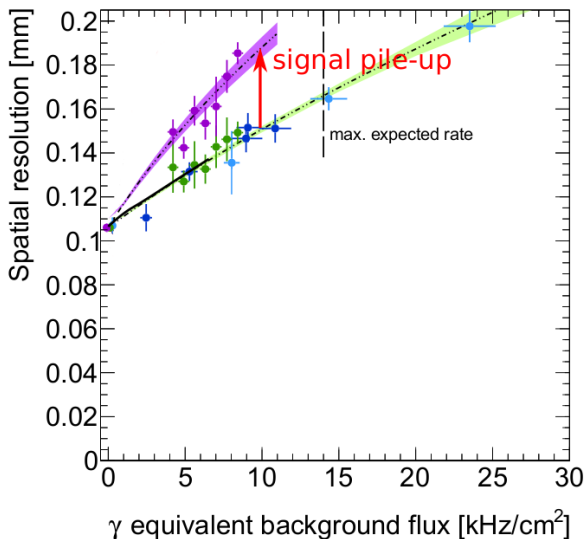
Signal Pile-Up

- Large undershoot from bipolar shaping
- Shift of a second threshold crossing
- Even loss of second hit is possible
- Efficiency loss

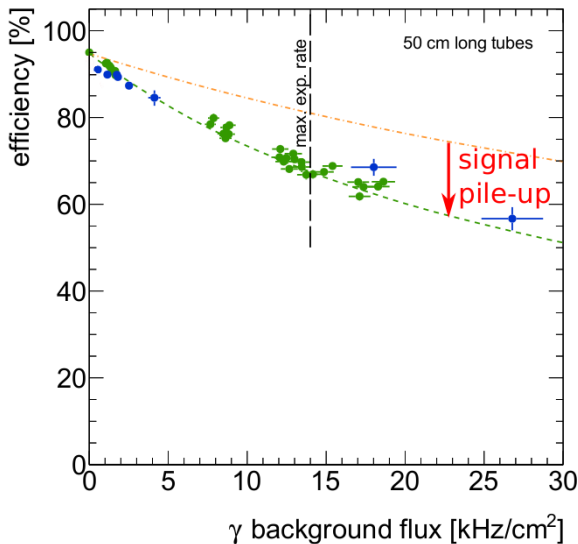
⇒ Still more potential in the sMDT



Signal Pile-Up



Signal Pile-Up



Base Line Restoration

- The aim is to get rid of the long signal tail

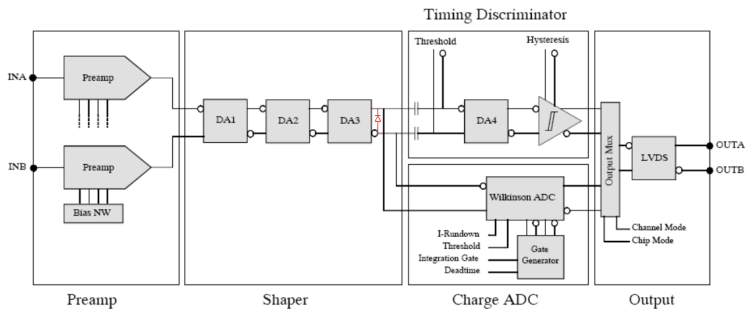
⇒ Negative signal part is unwanted

- Simplified idea:

Insertion of a diode

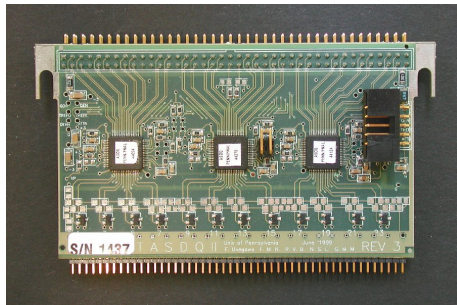
⇒ Negative part is 'cut' off

⇒ Lower deadtime



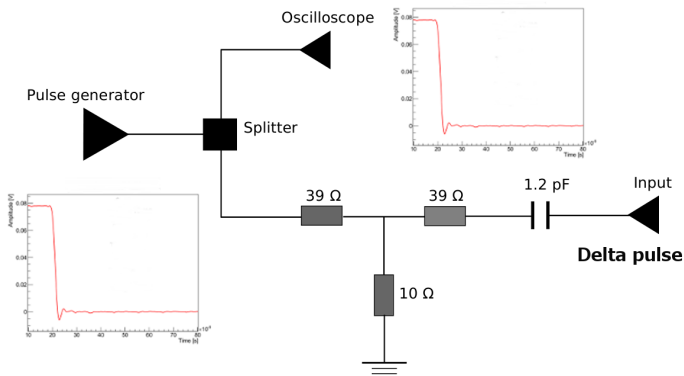
Testsetting

- Testboard with BLR electronics
- Delta pulse



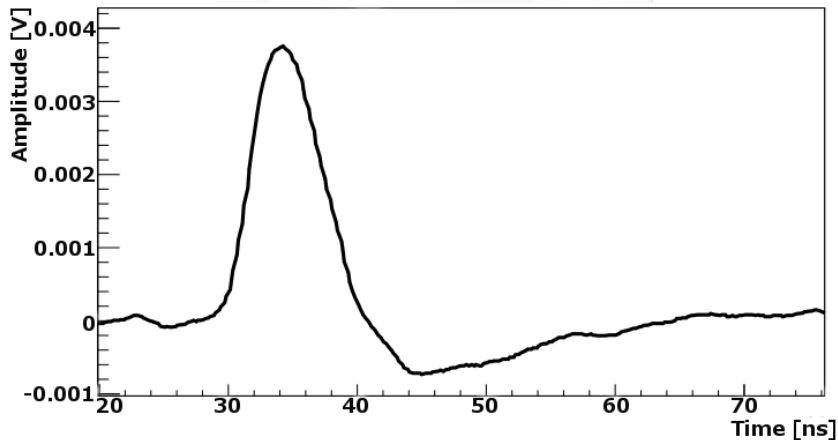
First Test of Readout Electronics with BLR

- Rectangular signal from pulse generator
 - Feeding the input via capacitor
- ⇒ Delta pulse at the input of the electronic



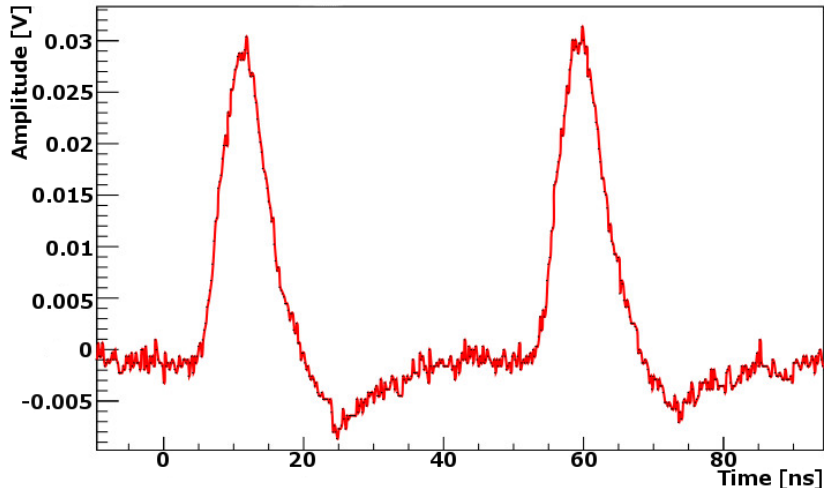
First Test of Readout Electronics with BLR

- Only a small undershoot
- Fast base line restoration



First Test of Readout Electronics with BLR

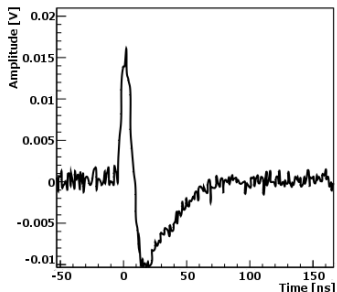
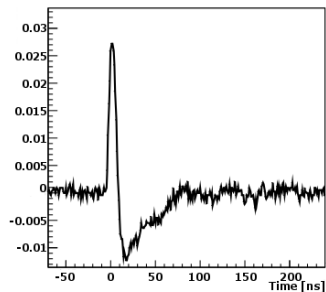
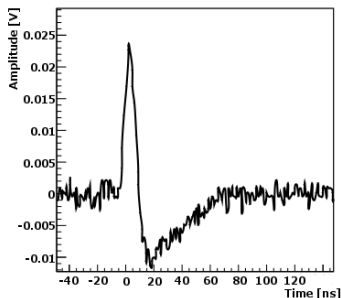
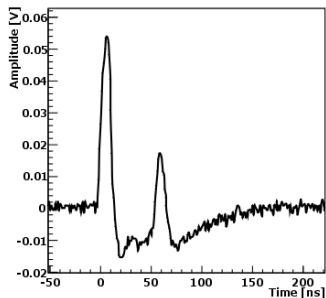
- No pile-up
- No loss of amplitude



First Test of Readout Electronics with BLR



First Test of Readout Electronics with BLR



Conclusion and Summary

- Signal pile-up lowers efficiency
- Shaping has to be improved
- Chip with BLR
 - Shows expected characteristic
 - Lowers deadtime
 - Shortens the undershoot
- Test measurements on a chambers
- Development of a new adjusted chip

Thank you for your attention